MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet













1. BASE

SOT - 23

3. COLLECTOR

2. EMITTER MARKING: G1

TRANSISTOR (NPN)

FEATURES

- Complementary to MMBT5401-MS
- Ideal for Medium Power Amplification and Switching

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	180	V
V _{CEO}	Collector-Emitter Voltage	160	V
V _{EBO}	Emitter-Base Voltage	6	V
Ic	Collector Current	600	mA
Pc	Collector Power Dissipation	300	mW
R _{OJA}	Thermal Resistance From Junction To Ambient	416	°C/W
T_{J}, T_{stg}	Operation Junction and Storage Temperature Range	-55∼+150	℃

ELECTRICAL CHARACTERISTICS (T_a=25°C unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =100μA, I _E =0	180			V
Collector-emitter breakdown voltage	V _{(BR)CEO} *	I _C =1mA, I _B =0	160			V
Emitter-base breakdown voltage	$V_{(BR)EBO}$	I _E =10μA, I _C =0	6			V
Collector cut-off current	I _{CBO}	V _{CB} =120V, I _E =0			50	nA
Emitter cut-off current	I _{EBO}	V _{EB} =4V, I _C =0			50	nA
	h _{FE(1)} *	V _{CE} =5V, I _C =1mA	80			
DC current gain	h _{FE(2)} *	V _{CE} =5V, I _C =10mA	100		300	
	h _{FE(3)} *	V _{CE} =5V, I _C =50mA	50			
Collector emitter saturation voltage	V _{CE(sat)1} *	I _C =10mA, I _B =1mA			0.15	V
Collector-emitter saturation voltage	V _{CE(sat)2} *	I _C =50mA, I _B =5mA			0.2	V
Page emitter ceturation voltage	V _{BE(sat)1} *	I _C =10mA, I _B =1mA			1	V
Base-emitter saturation voltage	V _{BE(sat)2} *	I _C =50mA, I _B =5mA			1	V
Transition frequency	f _T	V _{CE} =10V,I _C =10mA, f=100MHz	100		300	MHz
Collector output capacitance	C _{ob}	V _{CB} =10V, I _E =0, f=1MHz			6	pF

^{*}Pulse test: pulse width ≤300µs, duty cycle≤ 2.0%.

CLASSIFICATION OF h_{FE (2)}

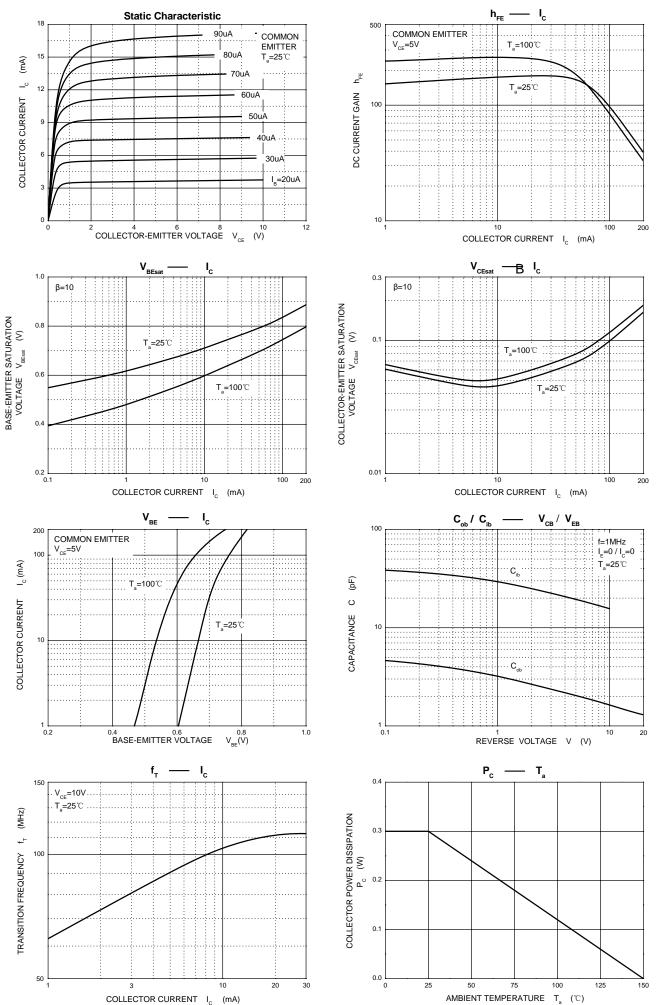
RANK	L	Н
RANGE	100-200	200-300



Semiconductor

Compiance

Typical Characteristics

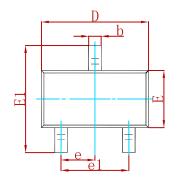


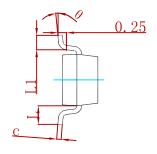


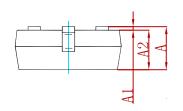




PACKAGE MECHANICAL DATA

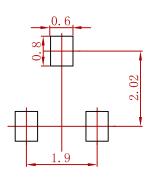






Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950) TYP	0.037	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MMBT5551-MS	SOT-23	3000



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